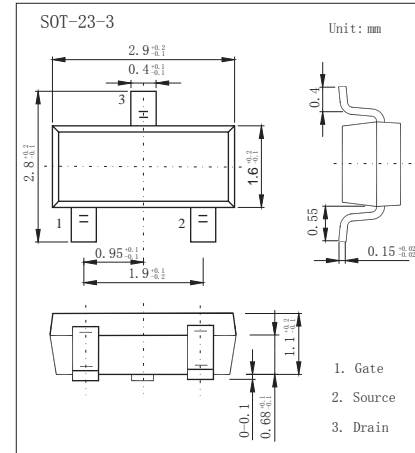
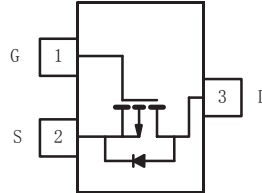


SI2301

P-Channel Enhancement MOSFET

- Features
- $V_{DS} (V) = -20V$
- $R_{DS(ON)} < 100m\Omega (V_{GS} = -4.5V)$
- $R_{DS(ON)} < 150m\Omega (V_{GS} = -2.5V)$



Absolute Maximum Ratings $T_a = 25^\circ C$

| Parameter | Symbol | 5 sec | Steady State | Unit |
|---|------------|--------------------|--------------|--------------|
| Drain-Source Voltage | V_{DS} | -20 | | V |
| Gate-Source Voltage | V_{GS} | ± 8 | | |
| Continuous Drain Current ($T_J = 150^\circ C$)*1 | I_D | $T_a = 25^\circ C$ | -3.2 | A |
| | | $T_a = 70^\circ C$ | -2.5 | |
| Pulsed Drain Current *2 | I_{DM} | -10 | | |
| Power Dissipation *1 | P_D | $T_a = 25^\circ C$ | 0.9 | W |
| | | $T_a = 70^\circ C$ | 0.57 | |
| Thermal Resistance..Junction- to-Ambient *1 | R_{thJA} | *3 | 120 | $^\circ C/W$ |
| | | | 140 | |
| Junction Temperature | T_J | 150 | | $^\circ C$ |
| Storage Temperature Range | T_{stg} | -55 to 150 | | |

*1 Surface Mounted on FR4 Board, $t \leq 5$ sec.

*2 Pulse width limited by maximum junction temperature.

*3 Surface Mounted on FR4 Board.

Electrical Characteristics Ta = 25 °C

| Parameter | Symbol | Test Conditions | Min | Typ | Max | Unit |
|---------------------------------------|---------------------|---|-------|------|-------|------|
| Drain-Source Breakdown Voltage | V _{DSS} | I _D =-250 μ A, V _{GS} =0V | -20 | | | V |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{DS} =-20V, V _{GS} =0V | | | -1 | μ A |
| | | V _{DS} =-20V, V _{GS} =0V, T _J =55 °C | | | -10 | |
| Gate-Body leakage current | I _{GSS} | V _{DS} =0V, V _{GS} =±8V | | | ±100 | nA |
| Gate Threshold Voltage | V _{GS(th)} | V _{DS} =V _{GS} I _D =-250 μ A | -0.45 | | -0.95 | V |
| Static Drain-Source On-Resistance | R _{DS(on)} | V _{GS} =-4.5V, I _D =-2.8A | | 80 | 100 | m Ω |
| | | V _{GS} =-2.5V, I _D =-2.0A | | 110 | 150 | |
| On state drain current *1 | I _{D(ON)} | V _{GS} =-4.5V, V _{DS} ≤ -5V | -6 | | | A |
| | | V _{GS} =-2.5V, V _{DS} ≤ -5V | -3 | | | |
| Forward Transconductance *1 | g _{FS} | V _{DS} =-5V, I _D =-2.8A | | 6.5 | | S |
| Input Capacitance *2 | C _{iss} | V _{GS} =0V, V _{DS} =-6V, f=1MHz | | 375 | | pF |
| Output Capacitance *2 | C _{oss} | | | 95 | | |
| Reverse Transfer Capacitance *2 | C _{rss} | | | 65 | | |
| Total Gate Charge *2 | Q _g | V _{GS} =-4.5V, V _{DS} =-6V, I _D =-2.8A | | 4.5 | 10 | nC |
| Gate Source Charge *2 | Q _{gs} | | | 0.7 | | |
| Gate Drain Charge *2 | Q _{gd} | | | 1.1 | | |
| Turn-On DelayTime *3 | t _{d(on)} | V _{GS} =-4.5V, V _{DS} =-6V, R _L =6 Ω, R _{GEN} =6 Ω I _D =-1.0A | | 20 | 30 | ns |
| Turn-On Rise Time *3 | t _r | | | 40 | 60 | |
| Turn-Off DelayTime *3 | t _{d(off)} | | | 30 | 45 | |
| Turn-Off Fall Time *3 | t _f | | | 20 | 30 | |
| Maximum Body-Diode Continuous Current | I _S | 5 sec | | | -0.72 | A |
| | | Steady State | | | -0.6 | |
| Diode Forward Voltage | V _{SD} | I _S =-0.75A, V _{GS} =0V | | -0.8 | -1.2 | V |

*1 Pulse test: PW ≤ 300us duty cycle ≤ 2%.

*2 For DESIGN AID ONLY, not subject to production testing.

*3 Switching time is essentially independent of operating temperature.

Marking

| | |
|---------|-----|
| Marking | A1* |
|---------|-----|

